STU12N60M2



N-channel 600 V, 0.395 Ω typ., 9 A MDmesh™ M2 Power MOSFET in an IPAK package

Datasheet - production data

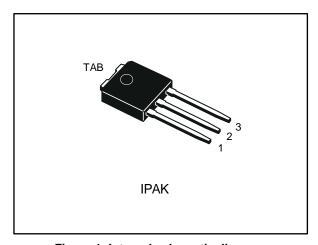
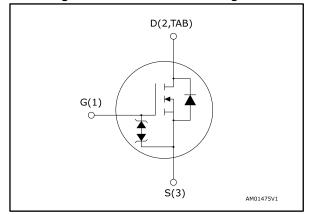


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	Ртот
STU12N60M2	600 V	0.450 Ω	9 A	85 W

- Extremely low gate charge
- Excellent output capacitance (C_{OSS}) profile
- 100% avalanche tested
- Zener-protected

Applications

Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STU12N60M2	12N60M2	IPAK	Tube

Contents STU12N60M2

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STU12N60M2 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	±25	V
1-	Drain current (continuous) at T _{case} = 25 °C	9	۸
I _D	Drain current (continuous) at T _{case} = 100 °C	5.7	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	36	А
P _{TOT}	Total dissipation at T _{case} = 25 °C	85	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	15	V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	50	V/IIS
T _{stg}	Storage temperature	-55 to 150	°C
T _j	Operating junction temperature	-55 10 150	C

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	1.47	°C AA7
R _{thj-amb}	Thermal resistance junction-ambient	62.5 °C/V	

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR} ⁽¹⁾	Avalanche current, repetitive or not repetitive	2.6	Α
E _{AR} ⁽²⁾	Single pulse avalanche energy	117	mJ

Notes:

 $^{^{\}left(1\right)}$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ $I_{SD} \leq 9$ A, di/dt=400 A/µs; $V_{DS(peak)} < V_{(BR)DSS}, \ V_{DD} = 80\% \ V_{(BR)DSS}.$

 $^{^{(3)}}$ V_{DS} ≤ 480 V.

 $^{^{(1)}}$ Pulse width limited by T_{jmax} .

 $^{^{(2)}}$ starting $T_j = 25~^{\circ}C,~I_D = I_{AR},~V_{DD} = 50~V.$

Electrical characteristics STU12N60M2

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
	Zoro goto voltago droin	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	
I _{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 \text{ °C}$			100	μΑ
I _{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±10	μΑ
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 4.5 A		0.395	0.450	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		1	538	ı	
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$	-	29	•	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0 V$	ı	1.1	1	ρ.
Coss eq. (1)	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$ V	1	106	1	pF
R_{G}	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	7	-	Ω
Q_g	Total gate charge	$V_{DD} = 400 \text{ V}, I_{D} = 9 \text{ A},$	•	16	1	
Q_gs	Gate-source charge	V _{GS} = 10 V (see <i>Figure 15</i> :	•	2.3	•	nC
Q_{gd}	Gate-drain charge	"Gate charge test circuit")	•	8.5	•	

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 4.5 \text{ A}$	1	9.2	1	
t _r	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 14: "Switching	-	9.2	-	
t _{d(off)}	Turn-off delay time	times test circuit for	1	5	1	ns
t _f	Fall time	resistive load" and Figure 19: "Switching time waveform")	•	18	-	

 $^{^{(1)}}$ $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 8: Source-drain diode

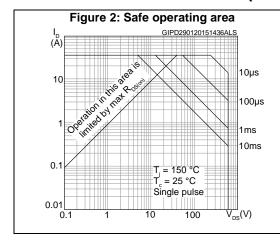
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		1		9	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		36	Α
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 9 \text{ A}$	1		1.6	V
t _{rr}	Reverse recovery time	$I_{SD} = 9 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	284		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 60 V (see Figure 16: "Test circuit for inductive	1	2.4		μC
I _{RRM}	Reverse recovery current	load switching and diode recovery times")	1	17		Α
t _{rr}	Reverse recovery time	$I_{SD} = 9 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	404		ns
Q _{rr}	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 ^{\circ}\text{C}$ (see Figure 16: "Test circuit	•	3.5		μC
I _{RRM}	Reverse recovery current	for inductive load switching and diode recovery times")	-	17.5		А

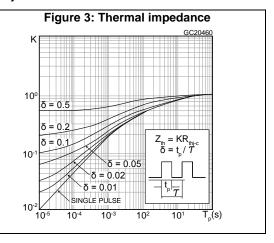
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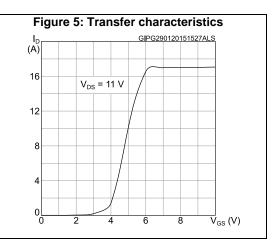
⁽¹⁾ Pulse width is limited by safe operating area.

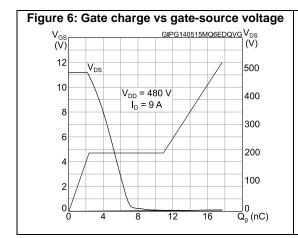
⁽²⁾ Pulse test: pulse duration = 300 μ s, duty cycle 1.5%.

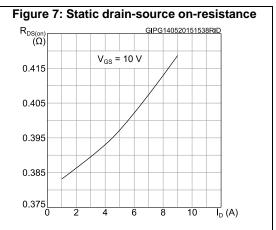
2.1 Electrical characteristics (curves)











STU12N60M2 Electrical characteristics

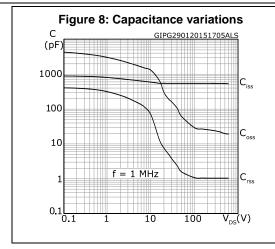
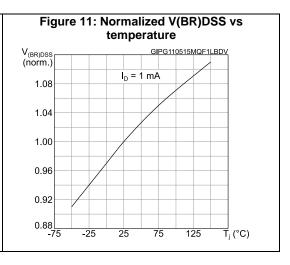
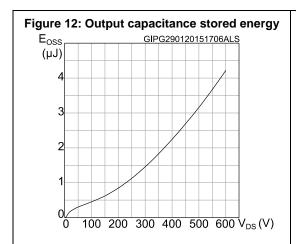


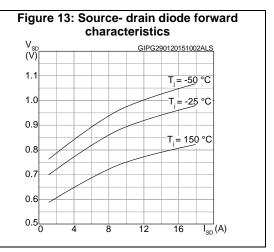
Figure 9: Normalized gate threshold voltage vs temperature

V_GS(III)
1.10
1.00
I_D = 250 µA
0.90
0.80
0.70
-50
0
50
100
T_j°C)

Figure 10: Normalized on-resistance vs temperature R_{DS(on)} (norm.) GIPG110515MQF1LRON V_{GS} = 10 V 2.2 1.8 1.4 1.0 0.6 0.2 -75 -25 25 75 125 T_i (°C)



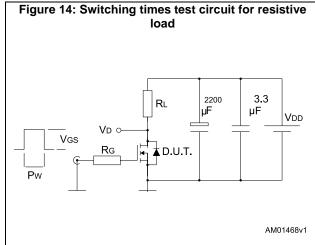




Test circuits STU12N60M2

3 Test circuits





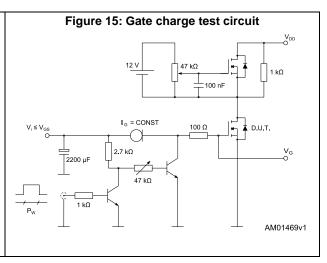


Figure 16: Test circuit for inductive load switching and diode recovery times

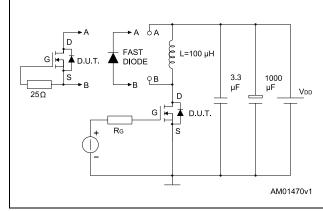
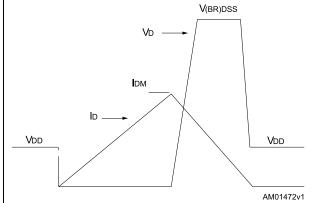
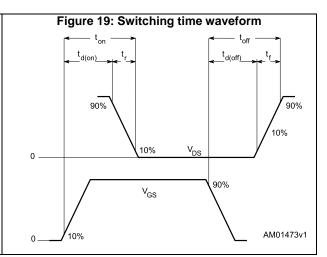


Figure 17: Unclamped inductive load test circuit

Figure 18: Unclamped inductive waveform





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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 IPAK (TO-251) Type A package information

L2 D b2 (3x) Н **b** (3x) A 1 *B5* 0068771_IK_typeA_rev13 e 1

Figure 20: IPAK (TO-251) type A package outline

Table 9: IPAK (TO-251) type A package mechanical data

		mm	
Dim.	Min.	Тур.	Max.
A	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
е		2.28	
e1	4.40		4.60
Н		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

STU12N60M2 Revision history

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
22-May-2015	1	First release.

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